

Notice of References CitedApplication/Control No.
09/693,976Applicant(s)/Patent Under
Re examination
CASA VANT ET AL.Examiner
Aaron C Perez-DapleArt Unit
2121

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,182,258	01-2001	Hollander, Yoav	714/739
	B	US-6,477,683	11-2002	Killian et al.	716/1
	C	US-6,233,540	05-2001	Schaumont et al.	703/14
	D	US-6,243,852	06-2001	Yoshikawa, Ko	716/18
	E	US-6,185,726	02-2001	Chou, Chen-Chi	716/18
	F	US-6,321,363	11-2001	Huang et al.	716/4
	G	US-5,953,519	09-1999	Fura, David A.	716/18
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Gupta et al., "Toward formalizing a validation methodology using simulation coverage," Design Automation Conference, 1997. Proceedings of the 34th, June 9-13, 1997 Pages: 740 - 745.
	V	Fallah et al., "Simulation Vector Generation from HDL Descriptions for Observability-Enhanced Statement Coverage," Proc. 36 Design Automation Conf., 1999, pgs. 158-167.
	W	Ganai et al., "Enhancing Simulation with BDDs and ATPG," Proc. Design Automation Conference, 1999, pgs. 385-390
	X	Geist et al., "Coverage-directed test generation using symbolic techniques," In Proceedings of the International Conference on Formal Methods in CAD, pgs. 143-158, Nov. 1996.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.